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# NEAR-FIELD POWER DENSITY EVALUATION REPORT

### **Applicant Name**

Samsung Electronics Co., Ltd. 129, Samsung-ro, Maetan dong, Yeongtong-gu, Suwon-si Gyeonggi-do, 16677, Korea

### Date of Testing

10/07/2021 - 11/02/2021 **Test Site/Location** PCTEST, Columbia, MD, USA **Document Serial No:** 1M2109080099-22.A3L (Rev 1)

ECC	<b>ID</b> •		
гсс	ID.		

A3LSMS901U

**APPLICANT:** 

SAMSUNG ELECTRONICS CO., LTD.

DUT Type:	Portable Handset
Application Type:	Certification
FCC Rule Part(s):	CFR §2.1093
Model:	SM-S901U
Additional Model (s):	SM-S901U1

Band & Mada	Tx Frequency	Measured psPD	Reported psPD		
Band & Mode	MHz	mW/cm²	mW/cm²		
n258	24250 - 24450; 24750 - 25250	0.453	0.891		
n261	27500 - 28350	0.519	0.891		
n260	n260 37000 - 40000		0.891		
Total E	xposure Ratio	0.986			
	Verdict	P/	ASS		

Note: This revised Test Report supersedes and replaces the previously issued test report on the same subject device for the same type of testing as indicated. Please discard or destroy the previously issued test report(s) and dispose of it accordingly.

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them. Test results reported herein relate only to the item(s) tested.

1 Randy Ortanez President



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### **APPENDIX A: POWER DENSITY TEST PLOTS APPENDIX B: SYSTEM VERIFICATION PLOTS APPENDIX C: TOTAL EXPOSURE RATIO** APPENDIX D: DUT ANTENNA DIAGRAM AND TEST SETUP PHOTOGRAPHS **APPENDIX E: PROBE AND VERIFICATION SOURCE CALIBRATION CERTIFICATES**

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# 1 DEVICE UNDER TEST

### 1.1 NR FR2 Checklist

NR FR2 Operations Information						
Form Factor	Portable Handset					
Subcarrier Spacing (kHz)	120					
Total Number of Supported Uplink CCs (SISO)	2					
Total Number of Supported Uplink CCs (MIMO)	2					
Total Number of Supported DL CCs	8					
CP-OFDM Modulations Supported in UL	QPSK, 16QAM, 64QAM, 256QAM					
DFT-s-OFDM Modulations Supported in UL	PV2 BPSK, QPSK, 16QAM, 64QAM, 256QAM					
LTE Anchor Bands	n258: 2/5/12/14/30/66, n261: 2/5/12/13/48/66, n260: 2/5/12/13/14/30/48/66					
NR FR1 Anchor Bands	n258: 2/5/12/30/66, n261: 2/5/66/77, n260: 2/5/12/30/66/77					
Duplex Type (mmWave)	TDD					

NR FR2 Channels & Frequencies									
NR Band	Bandwidth	Low		N	lid	High			
	(MHz)	Channel Frequency (MHz)		Channel	Frequency (MHz)	Channel	Frequency (MHz)		
n258	100	2018333	24350.04	2025833	24800.04	2032499	25200.00		
n258	50	2018333	24350.04	2025833	24800.04	2032915	25224.96		
n261	100	2071667	27550.08	2077915 27924.96		2084165	28299.96		
n261	50	2071249	27525.00	2077915	27924.96	2084581	28324.92		
n260	100	2229999	37050.00	2254165	38499.96	2278331	39949.92		
n260	50	2229599	37026.00	2254165	38499.96	2278749	39975.00		

## 1.2 Time-Averaging Algorithm for RF Exposure Compliance

The device is enabled with Qualcomm® Smart Transmit (GEN2) feature. This feature performs time averaging algorithm in real time to control and manage transmitting power and ensure the time-averaged RF exposure is in compliance with FCC requirements all the time. Refer to Compliance Summary document for detailed description of Qualcomm® Smart Transmit. Note that WLAN operations are not enabled with Smart Transmit.

The Smart Transmit algorithm maintains the time-averaged transmit power, in turn, time-averaged RF exposure of *SAR\_design\_target* or *PD\_design\_target*, below the predefined time-averaged power limit (i.e., *P*<sub>limit</sub> for sub-6 radio, and *input.power.limit* for 5G mmW NR), for each characterized technology and band (see RF Exposure Part 0 Test Report).

Smart Transmit allows the device to transmit at higher power instantaneously when needed, but manages power limiting to maintain time-averaged transmit power to *input.power.limit*.

The purpose of this report (Part 1 test) is to demonstrate that the EUT meets FCC PD limits when transmitting in static transmission scenario at maximum allowable time-averaged power level given by *input.power.limit.* 

## 1.3 Power Density Design Target and Uncertainty

Power Density Design Specifications							
PD_design_target (mW/cm²)	0.631						
Design Related Total Uncertainty (dB)	2.0						

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## 1.4 Input Power Specifications

All power density measurements for this device were performed at the *input.power.limit* given in below tables. Input power is per antenna element and polarization for each antenna module. When input.power.limit is calculated to be above the maximum input power, the device is limited to the maximum input power.

 Ivvave		JUINIFO	aten input.power
Band	Beam ID 1	Beam ID 2	input.power.limit
n258	0	-	11.7
n258	2	-	10.1
n258	4	-	8.9
n258	6	-	9.1
n258	8	-	11.0
n258	10	-	8.3
n258	11	-	7.2
n258	12	-	5.7
n258	13	-	83
n258	18	-	7.8
n258	10	_	7.5
m2E0	20	-	7:5
m2E0	20	-	3.9
11258	24	-	3.0
n258	25	-	2.7
n258	26	-	3.1
n258	27	-	2.7
n258	28	-	2.2
n258	34	-	2.6
n258	35	-	3.5
n258	36	-	2.9
n258	37	-	3.5
n258	-	128	10.2
n258	-	130	9.6
n258	-	132	9.1
n258	-	134	9.4
n258	-	136	10.3
n258	-	138	7.4
n258	-	139	6.8
n258		140	5.8
n258		140	5.8
n250	-	141	7.0
m250	-	140	7.0
11256	-	147	6.7
n258	-	148	6.5
n258	-	152	3.7
n258	-	153	2.8
n258	-	154	2.7
n258	-	155	2.6
n258	-	156	1.6
n258	-	162	2.5
n258	-	163	2.7
n258	-	164	2.9
n258	-	165	2.0
n258	0	128	7.0
n258	2	130	6.2
n258	4	132	5.6
n258	6	134	5.9
n258	8	136	6.8
n258	10	138	3.9
n258	11	139	3.3
n258	12	140	2.1
n250	12	140	4.0
112.30	10	141	4.0
11258	18	140	3.7
n258	19	147	3.7
n258	20	148	3.0
n258	24	152	-0.5
n258	25	153	-1.1
n258	26	154	-0.6
n258	27	155	-1.3
n258	28	156	-1.5
n258	34	162	-1.3
n258	35	163	-0.6
n258	36	164	-0.7
n258	37	165	-1.1

Table 1-1											
5G mmWave NR n258 M Patch input.power.limit											
	-		_		_						

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Band	Beam ID 1	Beam ID 2	input.power.limit
n258	1	-	10.1
n259	2	_	12.1
11256	3	-	12.1
n258	5	-	11.9
n258	7	-	11.9
n258	9	-	12.3
112.50		_	12.5
n258	14	-	9.2
n258	15	-	8.0
n258	16	_	77
	10		7.7
n258	1/	-	7.5
n258	21	-	8.1
n258	22	-	72
-250			8.1
11258	23	-	8.1
n258	29	-	5.2
n258	30	-	4.2
n259	21	_	25
112.30	31	-	3.5
n258	32	-	3.9
n258	33	-	4.4
n259	29	_	1 9
112.38	30	-	4.8
n258	39	-	3.6
n258	40	-	4.0
n258	41	-	4.2
112.50	41	130	4.2
n258	-	129	10.1
n258	-	131	10.2
n258	-	133	10.7
112.50	_	135	10.7
n258	-	135	11.1
n258	-	137	11.5
n258	_	1/12	9.1
112.50		142	5.1
n258	-	143	7.9
n258	-	144	6.2
n258	-	145	79
1250		143	0.7
n258	-	149	8.7
n258	-	150	7.4
n258	-	151	72
11250		151	7.2
n258	-	157	4.9
n258	-	158	3.5
n258	-	159	3.2
		100	2.0
11256	-	100	5.0
n258	-	161	3.3
n258	-	166	3.9
n2E9		167	2.2
11258	-	101	5.3
n258	-	168	3.1
n258	-	169	3.3
n259	1	120	6.2
11258	1	129	0.3
n258	3	131	7.4
n258	5	133	7.6
n258	7	135	77
112.50	,	107	,.,
n258	у	137	8.1
n258	14	142	5.8
n258	15	143	4.8
112.50	15	145	
n258	16	144	3.7
n258	17	145	4.0
n258	21	149	6.2
250	22	100	1.2
11258	22	130	4.0
n258	23	151	4.1
n258	29	157	1.3
250	20	100	0.7
n258	30	128	0.7
n258	31	159	-0.2
n258	32	160	-0.4
	22	100	5.4
n258	55	101	-0.1
n258	38	166	0.8
n258	39	167	03
	40	100	0.0
11258	40	τοδ	0.0
n258	41	169	-0.1

Table 1-2 5G mmWave NR n258 N Patch input.power.limit

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Band	Beam ID 1	Beam ID 2	input.power.limit
n261	0	-	11.2
n261	2	_	9.9
11201	2	-	5.5
n261	4	-	10.7
n261	6	-	9.5
n261	8	-	10.5
n261	10		9.1
11201	10	-	0.1
n261	11	-	6.9
n261	12	-	6.8
n261	13	-	7 9
-201	10		7.5
n261	18	-	1.1
n261	19	-	6.7
n261	20	-	6.6
n261	24	-	3.5
-201	25		3.0
11261	25	-	3.9
n261	26	-	3.4
n261	27	-	2.8
n261	28	-	2.6
n2C1	24	-	2.0
ΠΖΦΙ	34	-	3.5
n261	35	-	3.6
n261	36	-	2.7
n261	37	-	2.5
- 201	57	122	2.3
n261	-	128	8.7
n261	-	130	8.8
n261	-	132	8.9
n261	_	13/	9.1
- 201		134	5.1
n261	-	136	9.7
n261	-	138	6.3
n261	-	139	5.7
n261		140	E 4
11201	-	140	5.4
n261	-	141	6.0
n261	-	146	5.9
n261	-	147	5.7
m201		140	5.7
n261	-	148	5.7
n261	-	152	1.9
n261	-	153	1.9
n261	_	154	2.2
11201	-	134	2.2
n261	-	155	2.1
n261	-	156	1.7
n261	-	162	1.7
n261		162	2.2
11201	-	103	2.3
n261	-	164	2.3
n261	-	165	1.7
n261	0	128	6.2
n261	2	120	5.0
11201	2	130	5.9
n261	4	132	6.2
n261	6	134	6.0
n261	8	136	6.5
n2C1	10	120	3.3
11201	10	138	3.3
n261	11	139	3.1
n261	12	140	3.0
n261	13	141	3 5
n201	10	140	3.5
11201	18	140	3.9
n261	19	147	3.2
n261	20	148	2.9
n261	24	152	-15
-201	27	152	1.5
n261	25	153	-0.7
n261	26	154	-0.3
n261	27	155	-0.7
n261	20	156	_1 0
11201	20	100	-1.2
n261	34	162	-1.3
n261	35	163	-0.2
n261	36	164	-0.6
n2C1	27	107	1.0
11201	5/	201	-1.2

Table 1-3	
5G mmWave NR n261 M Patch	input.power.limit

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			ton inputipononi
Band	Beam ID 1	Beam ID 2	input.power.limit
n261	1	-	9.9
n261	2		0 1
N261	3	-	9.1
n261	5	-	9.2
n261	7	-	9.2
n261	9	-	10.2
1201			10.2
n261	14	-	6.3
n261	15	-	5.8
n261	16	-	5.6
n261	17	_	77
11201	17	-	7.7
n261	21	-	5.9
n261	22	-	5.7
n261	23	-	6.6
n261	29	_	2.4
11201	20		2.4
n261	30	-	1.6
n261	31	-	1.8
n261	32	-	2.2
n261	33	-	3.0
m2C1			3.0
n261	38	-	2.0
n261	39	-	1.6
n261	40	-	1.9
n261	41	-	2.5
n261		120	Q 1
11201	-	123	3.1
n261	-	131	9.9
n261	-	133	10.1
n261	-	135	9.6
n261	-	137	9.2
n261		142	63
-11201	-	142	0.3
n261	-	143	6.3
n261	-	144	6.8
n261	-	145	6.5
n261	-	149	7.0
n261		150	6.4
11201	-	130	0.4
n261	-	151	6.8
n261	-	157	2.7
n261	-	158	2.1
n261	-	159	23
-261		100	2.5
N261	-	160	2.1
n261	-	161	3.7
n261	-	166	2.3
n261	-	167	2.3
n261		169	2.2
11201	-	100	2.2
n261	-	169	2.6
n261	1	129	5.8
n261	3	131	5.7
n261	5	133	6.0
n201		125	5.0
11201	/	132	3.8
n261	9	137	6.0
n261	14	142	2.8
n261	15	143	2.5
n261	16	144	3.1
-201	10	145	5.4
n261	1/	145	5.2
n261	21	149	3.2
n261	22	150	3.0
n261	23	151	3.2
n261	20	157	_1 1
m2C1	23	150	-1.1
n261	30	158	-1.5
n261	31	159	-1.5
n261	32	160	-1.4
n261	33	161	-0.7
n261	39	166	-1 4
11201	30	100	-1.4
n261	39	167	-1.4
n261	40	168	-1.6
n261	41	169	-11

Table 1-4 5G mmWave NR n261 N Patch input.power.limit

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Band	Beam ID 1	Beam ID 2	input.power.limit
n260	0	-	11.9
n260	2	-	13.1
n260	4	_	12.6
11200	4	-	12.0
n260	6	-	12.5
n260	8	-	12.5
n260	10	-	10.5
n260	11	-	10.0
n260	12	-	9.7
n260	13	_	10.2
1200	10		10.2
n260	18	-	9.3
n260	19	-	9.5
n260	20	-	9.9
n260	24	-	6.4
n260	25	-	7.8
n260	26	-	6.3
n260	27	_	63
1200	27	-	0.3
n260	28	-	5.9
n260	34	-	/.1
n260	35	-	7.1
n260	36	-	6.4
n260	37	-	5.7
n260	_	128	11 9
n260		120	12.5
11200	-	130	12.0
n260	-	132	12.0
n260	-	134	12.4
n260	-	136	12.0
n260	-	138	9.0
n260	-	139	9.8
n260	-	140	9.7
n260		140	9.9
11200	-	141	8.8
n260	-	146	9.4
n260	-	147	9.7
n260	-	148	9.4
n260	-	152	5.3
n260	-	153	5.4
n260	-	154	65
n260		154	6.5
11200	-	155	0.2
n260	-	156	5.8
n260	-	162	5.6
n260	-	163	5.9
n260	-	164	5.9
n260	-	165	6.8
n260	n	128	8.4
n200	2	120	0.4
11260	2	130	9.1
n260	4	132	8.9
n260	6	134	9.0
n260	8	136	8.8
n260	10	138	6.5
n260	11	139	6.4
n260	12	140	50
n200	12	141	5.5
11260	13	141	0.2
n260	18	146	/.0
n260	19	147	6.4
n260	20	148	7.7
n260	24	152	2.3
n260	25	153	2.1
n260	25	154	2.1
1200	20	104	2.3
n260	2/	155	2.0
n260	28	156	2.2
n260	34	162	2.4
n260	35	163	2.4
n260	36	164	2.0
n260	37	165	19
11200	57	100	1.3

Table 1-5				
5G mmWave NR n260 M Patch input.power.limit				

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David	D		in the second line it
Band	Beam ID 1	Beam ID 2	input.power.limit
n260	1	-	10.0
n260	3	-	8.7
n260	5	-	8.8
n260	7	_	8.4
11200	,	-	8.4
n260	9	-	7.9
n260	14	-	5.7
n260	15	-	6.5
n260	16	-	5.4
n260	17	_	5.4
11200	17	-	5.4
n260	21	-	6.6
n260	22	-	5.2
n260	23	-	5.4
n260	29	-	2.2
n260	30	_	3.0
11200	30		3.0
n260	31	-	2.1
n260	32	-	1.4
n260	33	-	1.7
n260	38	-	2.8
n260	39	-	19
11200	35	_	1.5
n260	40	-	1.2
n260	41	-	1.7
n260	-	129	6.6
n260	-	131	7.4
n260	-	122	73
11200	-	135	7.3
n260	-	135	7.2
n260	-	137	7.2
n260	-	142	4.1
n260	-	143	4.4
n260		144	4.5
11200	-	144	4.5
n260	-	145	4.2
n260	-	149	3.6
n260	-	150	4.6
n260	-	151	4.4
n260		157	1.2
1260	-	157	1.2
n260	-	158	0.1
n260	-	159	1.0
n260	-	160	1.1
n260	-	161	0.8
*200		101	0.0
n260	-	166	0.5
n260	-	167	-0.1
n260	-	168	1.6
n260	-	169	0.8
n260	1	129	4.0
1200		123	4.0
n260	3	131	4.2
n260	5	133	4.3
n260	7	135	4.4
n260	9	137	3.5
n260	1/	142	2.6
11200	14	142	2.0
n260	15	143	2.1
n260	16	144	1.3
n260	17	145	1.2
n260	21	149	1.3
n260	22	150	2.2
1200	22	150	1.2
n260	23	151	1.3
n260	29	157	-2.5
n260	30	158	-2.2
n260	31	159	-27
n260	27	160	
11200	52	100	-2.8
n260	33	161	-3.3
n260	38	166	-2.2
n260	39	167	-2.6
n260	40	168	-2 5
11200		100	-2.5
n260	41	102	-3.2

Table 1-6
5G mmWave NR n260 N Patch input.power.limit

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#### 1.5 **DUT Antenna Locations**

The table below indicates the surfaces evaluated for near field power density (part 1) evaluation. Refer to RF Exposure Part 0 Test Report for justification of these worst-surfaces

Table 1-7 Device Surfaces								
Band	Antenna	Antenna Type	Back	Front	Тор	Bottom	Right	Left
n258	м	Patch	Yes	No	No	No	No	No
n258	N	Patch	Yes	No	No	No	Yes	No
n261	М	Patch	Yes	No	No	No	No	No
n261	N	Patch	No	No	No	No	Yes	No
n260	М	Patch	Yes	No	No	No	No	No
n260	N	Patch	Yes	Yes	No	No	Yes	No

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## 1.6 Simultaneous Transmission Capabilities

According to FCC KDB Publication 447498 D01v06, transmitters are considered to be operating simultaneously when there is overlapping transmission, with the exception of transmissions during network hand-offs with maximum hand-off duration less than 30 seconds.

This device contains multiple transmitters that may operate simultaneously, and therefore requires a simultaneous transmission analysis according to FCC KDB Publication 447498 D01v06 4.3.2 procedures.

Table 1-8

Simultaneous Tx						
No.	Capable Transmit Configuration	Head	Body-worn	Wireless Router	Phablet	Notes
1	LTE + 5G NR FR2	Yes	Yes	N/A	Yes	
2	LTE + 2.4 GHz WLAN MIMO + 5G NR FR2	Yes	Yes	Yes	Yes	
3	LTE + 5 GHz WLAN Ant 1 + 5G NR FR2	Yes	Yes	Yes	Yes	
4	LTE + 5 GHz WLAN MIMO + 5G NR FR2	Yes	Yes	Yes	Yes	
5	LTE + 2.4 GHz WLAN MIMO + 5 GHz WLAN MIMO + 5G NR FR2	Yes	Yes	Yes	Yes	
6	LTE + 2.4 GHz Bluetooth + 5G NR FR2	Yes^	Yes	Yes^	Yes	^Bluetooth Tethering is considered
7	LTE + 2.4 GHz WLAN Ant 2 + 2.4 GHz Bluetooth + 5G NR FR2	Yes^	Yes	Yes^	Yes	^Bluetooth Tethering is considered
8	LTE + 2.4 GHz Bluetooth + 5 GHz WLAN Ant 1 + 5G NR FR2	Yes^	Yes	Yes^	Yes	^Bluetooth Tethering is considered
9	LTE + 2.4 GHz Bluetooth + 5 GHz WLAN MIMO + 5G NR FR2	Yes^	Yes	Yes^	Yes	^Bluetooth Tethering is considered
10	LTE + 2.4 GHz WLAN Ant 2 + 2.4 GHz Bluetooth + 5 GHz WLAN Ant 1 + 5G NR FR2	Yes^	Yes	Yes^	Yes	^Bluetooth Tethering is considered
11	LTE + 2.4 GHz WLAN Ant 2 + 2.4 GHz Bluetooth + 5 GHz WLAN MIMO + 5G NR FR2	Yes^	Yes	Yes^	Yes	^Bluetooth Tethering is considered
12	5G NR FR1 + 5G NR FR2	Yes	Yes	N/A	Yes	
13	5G NR FR1 + 2.4 GHz WLAN MIMO + 5G NR FR2	Yes	Yes	Yes	Yes	
14	5G NR FR1 + 5 GHz WLAN Ant 1 + 5G NR FR2	Yes	Yes	Yes	Yes	
15	5G NR FR1 + 5 GHz WLAN MIMO + 5G NR FR2	Yes	Yes	Yes	Yes	
16	5G NR FR1 + 2.4 GHz WLAN MIMO + 5 GHz WLAN MIMO + 5G NR FR2	Yes	Yes	Yes	Yes	
17	5G NR FR1 + 2.4 GHz Bluetooth + 5G NR FR2	Yes^	Yes	Yes^	Yes	^Bluetooth Tethering is considered
18	5G NR FR1 + 2.4 GHz WLAN Ant 2 + 2.4 GHz Bluetooth + 5G NR FR2	Yes^	Yes	Yes^	Yes	^Bluetooth Tethering is considered
19	5G NR FR1 + 2.4 GHz Bluetooth + 5 GHz WLAN Ant 1 + 5G NR FR2	Yes^	Yes	Yes^	Yes	^Bluetooth Tethering is considered
20	5G NR FR1 + 2.4 GHz Bluetooth + 5 GHz WLAN MIMO + 5G NR FR2	Yes^	Yes	Yes^	Yes	^Bluetooth Tethering is considered
21	5G NR FR1 + 2.4 GHz WLAN Ant 2 + 2.4 GHz Bluetooth + 5 GHz WLAN Ant 1 + 5G NR FR2	Yes^	Yes	Yes^	Yes	^Bluetooth Tethering is considered
22	5G NR FR1 + 2.4 GHz WLAN Ant 2 + 2.4 GHz Bluetooth + 5 GHz WLAN MIMO + 5G NR FR2	Yes^	Yes	Yes^	Yes	^Bluetooth Tethering is considered

### NOTE:

- 1. 5G NR mmW Operations are limited to Non-Standalone (EN-DC) operations only.
- 2. NR antenna arrays cannot transmit simultaneously.
- 3. LTE + 5G NR FR2 Scenarios are limited to EN-DC combinations with anchor bands as shown in the NR FR2 checklist.
- 4. 2.4 GHz WLAN, and 2.4 GHz Bluetooth share the same antenna path and cannot transmit simultaneously.
- 5. This device supports time averaging smart transmit algorithm in WWAN. Smart transmit adds directly the time-averaged RF exposure from 4G/5G NR FR1 and time-averaged RF exposure from 5G mmW NR FR2 to ensure that the normalized RF exposure from both 4G/5G NR FR1 and 5G mmW NR FR2 does not exceed FCC limit.

### 1.7 Guidance Applied

- November 2017, October 2018, April 2019, November 2019 TCBC Workshop Notes
- SPEAG DASY6 System Handbook
- IEC TR 63170:2018
- FCC KDB 865664 D02 v01r04
- FCC KDB 447498 D01 v02r01

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#### 1.8 Bibliography

Table 1-9 **Bibliography** 

Disnography				
Report Type	Report Serial Number			
FCC SAR Evaluation Report (Part 1)	1M2109080099-01.A3L			
Power Density Part 0 Test Report				
RF Exposure Part 2 Test Report	1M2109080099-23.A3L			
RF Exposure Compliance Summary Report 1M2109080099-24.A3L				
Power Density Simulation Report				

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# 2 MEASUREMENT SYSTEM

### 2.1 Measurement Setup

Peak spatially averaged power density (psPD) measurements for mmWave frequencies were performed using the DASY6 with cDASY6 5G module. The DASY6 is made by Schmid & Partner Engineering AG (SPEAG) in Zurich, Switzerland and consists of a high precision robotics system (Staubli), robot controller, desktop computer, near-field probe, probe alignment sensor, and the 5G phantom. The robot is a six-axis industrial robot, performing precise movements to position the probe to the location (points) of maximum electromagnetic field (EMF).

## 2.2 SPEAG EUmmWVx Probe / E-Field 5G Probe

The EUmmWVx probe consists of two dipoles optimally arranged to obtain pseudo-vector information.

Frequency Range	750 MHz – 110 GHz
Dynamic Range	< 20 V/m – 10,000 V/m with PRE-10 (min < 50 V/m – 3,000 V/m)
Position Precision	< 0.2 mm (cDASY6)
Dimensions	Probe Overall Length: 320 mm Probe Body Diameter: 8 mm Probe Tip Length: 23 mm Probe Tip Diameter: Encapsulation 8 mm Distance from Probe Tip to Sensor X Calibration Point: 1.5 mm Distance from Probe Tip to Sensor Y Calibration Point: 1.5 mm
Applications	E-field measurements of 5G devices and other mm-wave transmitters operating above 10 GHz in < 2 mm distance from device (free-space) Power density, H-field and far-field analysis using total field reconstruction
Compatibility	cDASY6 + 5G-Module SW



Figure 2-1 EUmmWVx Probe

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### 2.3 Peak Spatially Averaged Power Density Assessment Based on E-field Measurements

Within a short distance from the transmitting source, power density was determined based on both electric and magnetic fields. Generally, the magnitude and phase of two components of either the E-field or H-field were needed on a sufficiently large surface to fully characterize the total E-field and H-field distributions. Nevertheless, solutions based on direct measurement of E-field and H-field can be used to compute power density. The general measurement approach used for this device was:

- a) The local E field on the measurement surface was measured at a reference location where the field is well above the noise level. This reference level was used at the end of this procedure to assess output power drift of the DUT during the measurement.
- b) The electric field on the measurement surface was scanned. Measurements are conducted according to the instructions provided by the measurement system manufacturer. Measurement spatial resolution can depend on the measured field characteristic and measurement methodology used by the system. The planar scan step size was configured at  $\lambda/4$ .
- c) For cDASY6, H-field was calculated from the measured E-field using a reconstruction algorithm. As the power density calculation requires knowledge of both amplitude and phase, reconstruction algorithms can also be used to obtain field information from the measured E-field data (e.g. the phase from the amplitude if only the amplitude is measured). H-field and phase data was reconstructed from repeated measurements (three per measurement point) on two measurement planes separated by  $\lambda/4$ .
- d) The total Peak spatially averaged power density (psPD) distribution on the evaluation surface is determined per the below equation. The spatial averaging area, *A*, is specified by the applicable exposure limits or regulatory requirements. A circular shape was used.

$$psPD = \frac{1}{2A_{av}} \qquad \iint_{A_{av}} || Re\{E \times H^*\} || dA$$

- e) The maximum spatial-average on the evaluation surface is the final quantity to determine compliance against applicable limits.
- f) The local E field reference value, at the same location as step 2, was re-measured after the scan was complete to calculate the power drift. If the drift deviated by more than 5%, the power density test and drift measurements were repeated.

## 2.4 Reconstruction Algorithm

Computation of the power density in general requires measurement information from the both E-field and H-field amplitudes and phases in the plane of incidence. Reconstruction of these quantities from pseudo-vector E-field measurements is feasible according to the manufacturer, as they are determined via Maxwell's equations. As such, the SPEAG reconstruction approach was based on the Gerchberg-Saxton algorithm, which benefits from the availability of the E-field polarization ellipse information obtained with the EUmmWVx probe.

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#### 3 **RF EXPOSURE LIMITS FOR POWER DENSITY**

#### 3.1 **Uncontrolled Environment**

UNCONTROLLED ENVIRONMENTS are defined as locations where there is the exposure of individuals who have no knowledge or control of their exposure. The general population/uncontrolled exposure limits are applicable to situations in which the general public may be exposed or in which persons who are exposed as a consequence of their employment may not be made fully aware of the potential for exposure or cannot exercise control over their exposure. Members of the general public would come under this category when exposure is not employment-related; for example, in the case of a wireless transmitter that exposes persons in its vicinity.

#### 3.2 **Controlled Environment**

CONTROLLED ENVIRONMENTS are defined as locations where there is exposure that may be incurred by persons who are aware of the potential for exposure, (i.e. as a result of employment or occupation). In general, occupational/controlled exposure limits are applicable to situations in which persons are exposed as a consequence of their employment, who have been made fully aware of the potential for exposure and can exercise control over their exposure. This exposure category is also applicable when the exposure is of a transient nature due to incidental passage through a location where the exposure levels may be higher than the general population/uncontrolled limits, but the exposed person is fully aware of the potential for exposure and can exercise control over his or her exposure by leaving the area or by some other appropriate means.

#### 3.3 **RF Exposure Limits for Frequencies Above 6 GHz**

Per §1.1310 (d)(3), the MPE limits are applied for frequencies above 6 GHz. Power Density is expressed in units of W/m<sup>2</sup> or mW/cm<sup>2</sup>.

Peak Spatially Averaged Power Density was evaluated over a circular area of 4 cm<sup>2</sup> per interim FCC Guidance for near-field power density evaluations per October 2018 TCB Workshop notes.

Human Exposure Limits Specified in FCC 47 CFR §1.1310						
Human Exposure to Radiofrequency (RF) Radiation Limits						
Frequency Range [MHz]Power Density [mW/cm²]Average Time [Minutes]						
(A) Limits	For Occupational / Controlled	Environments				
1,500 – 100,000	5.0	6				
(B) Limits For General Population / Uncontrolled Environments						
1,500 – 100,000	1.0	30				

Table 3-1	
Human Exposure Limits Specified in FCC 47 CFR §1	.1310

Note: 1.0 mW/cm<sup>2</sup> is 10 W/m<sup>2</sup>

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## 4 SYSTEM VERIFICATION

### 4.1 Test System Verification

The system was verified to be within ±0.66 dB of the power density targets on the calibration certificate according to the test system specification in the user's manual and calibration facility recommendation. The 0.66 dB deviation threshold represents the expanded uncertainty for system performance checks using SPEAG's mmWave verification sources. The same spatial resolution and measurement region used in the source calibration was applied during the system check.

The measured power density distribution of verification source was also confirmed through visual inspection to have no noticeable differences, both spatially (shape) and numerically (level) from the distribution provided by the manufacturer, per November 2017 TCBC Workshop Notes.



Figure 4-1 System Verification Setup Photo

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	30 GHZ VERIFICATIONS													
	System Verification													
System	ystem Frequency Date Source Probe Normal psPD (W/m <sup>2</sup> over 4 cm <sup>2</sup> ) Deviation (dB) Total psPD (W/m <sup>2</sup> over 4 cm <sup>2</sup> )													
			3/14	3/14	Measured	Target		Measured	Target					
R	30	10/07/2021	1045	9523	31.00	32.70	-0.23	31.40	33.20	-0.24	B1			
R	30	10/15/2021	1045	9523	30.90	32.70	-0.25	31.40	33.20	-0.24				
R	30	10/18/2021	1045	9523	31.20	32.70	-0.20	31.70	33.20	-0.20				
R	30	10/21/2021	1045	9523	30.90	32.70	-0.25	31.40	33.20	-0.24				
N	30	10/21/2021	1045	9541	31.00	32.70	-0.23	31.50	33.20	-0.23	B2			
R	30	11/02/2021	1045	9523	32.30	32.70	-0.05	32.80	33.20	-0.05				
Q	30	11/02/2021	1035	9389	32.30	31.00	0.18	32.70	31.00	0.23	B3			

### Table 4-1 30 GHz Verifications

Note: A 10 mm distance spacing was used from the reference horn antenna aperture to the probe element.

This includes 4.45 mm from the reference antenna horn aperture to the surface of the verification source plus 5.55 mm from the surface to the probe. The SPEAG software requires a setting of "5.55 mm" for the correct set up.

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# 5 POWER DENSITY DATA @ INPUT.POWER.LIMIT

## 5.1 Power Density Results

Power density measurements were performed with DUT transmitting at *input.power.limit* for one single beam for each polarization (H & V) and one beam-pair, for each antenna on each worst-surface.

							ME	EASUREN	IENT RESULT	rs					
Band	Module	Antenna Type	Frequency	Channel	Beam ID 1	Beam ID 2	input.power.limit	Signal Type	DUT S/N	Power Drift	Distance	DUT Surface	Normal psPD	Total psPD	Plot #
		21.5	MHz		v	н	dBm			dB	mm		mW/cm <sup>2</sup>	mW/cm <sup>2</sup>	
n258	м	Patch	25200.00	High	28	-	2.2	CW	UI20273M	0.20	2	Back	0.282	0.400	
n258	м	Patch	25200.00	High	-	156	1.6	cw	UI20273M	-0.18	2	Back	0.250	0.453	A1
n258	м	Patch	25200.00	High	28	156	-1.5	cw	UI20273M	0.20	2	Back	0.255	0.410	
n258	м	Patch	25200.00	High	26	-	3.1	cw	UI20217M	-0.01	10	Back	0.386	0.404	
n258	N	Patch	24350.04	Low	38	-	4.8	cw	UI20273M	-0.01	2	Back	0.141	0.223	
n258	N	Patch	25200.00	High	-	159	3.2	cw	UI20273M	-0.08	2	Back	0.128	0.138	
n258	N	Patch	24350.04	Low	33	161	-1.0	cw	UI20273M	-0.01	2	Back	0.040	0.074	
n258	N	Patch	24350.04	Low	31	-	3.5	cw	UI20273M	0.03	2	Right	0.338	0.399	A2
n258	N	Patch	25200.00	High	-	160	3.0	cw	UI20273M	0.13	2	Right	0.321	0.369	
n258	N	Patch	25200.00	High	32	160	-0.4	cw	UI20273M	-0.05	2	Right	0.326	0.394	
n258	Ν	Patch	24350.04	Low	29	157	1.3	cw	UI20273M	-0.03	10	Back	0.042	0.054	
	47 CFR §1.1310 - SAFETY LIMIT Spatial Average Uncontrolled Exposure / General Population										a	Power Der 1 mW/c veraged ove	nsity m² er 4 cm²		

Table 5-15G mmWave NR Band n258

### Table 5-2 5G mmWave NR Band n261

							ME	ASURE	IENT RESULT	rs					
Band	Module	Antenna Type	Frequency	Channel	Beam ID 1	Beam ID 2	input.power.limit	Signal Type	DUT S/N	Power Drift	Distance	DUT Surface	Normal psPD	Total psPD	Plot #
			MHz		v	н	dBm			dB	mm		mW/cm <sup>2</sup>	mW/cm²	
n261	м	Patch	27550.08	Low	37	-	2.5	cw	UI20273M	0.19	2	Back	0.342	0.448	
n261	м	Patch	27550.08	Low	-	162	1.7	cw	UI20273M	0.17	2	Back	0.360	0.504	A3
n261	м	Patch	27550.08	Low	24	152	-1.5	CW	UI20273M	0.16	2	Back	0.201	0.281	
n261	м	Patch	28299.96	High	-	163	2.3	CW	UI20217M	0.01	10	Back	0.335	0.363	
n261	N	Patch	28299.96	High	30	-	1.6	cw	UI20273M	0.16	2	Right	0.213	0.257	
n261	N	Patch	27550.08	Low	-	160	2.1	cw	UI20273M	-0.02	2	Right	0.458	0.519	A4
n261	N	Patch	28299.96	High	40	168	-1.6	cw	UI20273M	0.03	2	Right	0.249	0.283	
n261	N	Patch	27924.96	Mid	-	159	2.3	cw	UI20273M	0.20	10	Back	0.112	0.116	
	47 CFR §1.1310 - SAFETY LIMIT Spatial Average Uncontrolled Exposure / General Population										a	Power De 1 mW/c iveraged ove	nsity m² er 4 cm²		

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							<u> </u>	vave			00				
							ME	ASURE	MENT RESULT	rs					
Band	Module	Antenna Type	Frequency	Channel	Beam ID 1	Beam ID 2	input.power.limit	Signal Type	DUT S/N	Power Drift	Distance	DUT Surface	Normal psPD	Total psPD	Plot #
			MHz		v	н	dBm			dB	mm		mW/cm <sup>2</sup>	mW/cm <sup>2</sup>	
n260	м	Patch	38499.96	Mid	37	-	5.7	CW	UI20273M	-0.11	2	Back	0.249	0.333	
n260	м	Patch	39949.92	High	-	152	5.3	cw	UI20273M	0.09	2	Back	0.243	0.348	A5
n260	м	Patch	39949.92	High	37	165	1.9	cw	UI20273M	0.04	2	Back	0.252	0.339	
n260	м	Patch	39949.92	High	26	154	2.9	cw	UI20217M	0.04	10	Back	0.321	0.337	
n260	N	Patch	38499.96	Mid	30	-	3.3	cw	UI20273M	0.10	2	Back	0.148	0.188	
n260	N	Patch	38499.96	Mid	-	167	-0.1	cw	UI20273M	-0.18	2	Back	0.457	0.086	
n260	N	Patch	39949.92	High	39	167	-2.6	CW	UI20273M	-0.09	2	Back	0.067	0.071	
n260	N	Patch	39949.92	High	39	-	1.9	cw	UI20273M	0.09	10	Back	0.043	0.063	
n260	N	Patch	37050.00	Low	40	-	1.2	cw	UI20273M	-0.08	2	Front	0.047	0.052	
n260	N	Patch	37050.00	Low	15	-	6.5	cw	UI20217M	-0.06	2	Front	0.116	0.158	
n260	N	Patch	37050.00	Low	21	-	6.6	cw	UI20273M	-0.10	2	Front	0.103	0.150	
n260	N	Patch	38499.96	Mid	21	-	6.6	CW	UI20273M	-0.02	2	Front	0.126	0.191	
n260	N	Patch	37050.00	Low	39	-	1.9	cw	UI20217M	0.04	2	Front	0.171	0.174	
n260	N	Patch	38499.96	Mid	-	167	-0.1	cw	UI20273M	-0.01	2	Front	0.041	0.054	
n260	N	Patch	37050.00	Low	40	168	-2.5	cw	UI20273M	-0.02	2	Front	0.052	0.075	
n260	N	Patch	37050.00	Low	40	-	1.2	cw	UI20217M	-0.03	2	Right	0.192	0.212	A6
n260	N	Patch	38499.96	Mid	-	167	-0.1	cw	UI20217M	-0.19	2	Right	0.189	0.206	
n260	N	Patch	39949.92	High	33	161	-3.3	cw	UI20217M	0.08	2	Right	0.154	0.174	
	47 CFR §1.1310 - SAFETY LIMIT Spatial Average Uncontrolled Exposure / General Population										a	Power Der 1 mW/c	nsity m² ər 4 cm²		

Table 5-3 5G mmWave NR Band n260

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## 5.2 Power Density Test Notes

General Notes:

- 1. The manufacturer has confirmed that the devices tested have the same physical, mechanical and thermal characteristics and are within operational tolerances expected for production units.
- 2. Batteries are fully charged at the beginning of the measurements. The DUT was connected to a wall charger for some measurements due to the test duration. It was confirmed that the charger plugged into this DUT did not impact the near-field PD test results.
- 3. Power density was calculated by repeated E-field measurements on two measurement planes separated by  $\lambda/4$ .
- 4. DUT was configured to transmit with a manufacturer provided test software to control specific antenna(s), Beam ID(s), and signal type to ensure the test configurations constant for the entire evaluation.
- 5. This device utilizes power reduction for some WLAN wireless modes and technologies for simultaneous transmission compliance. These mechanisms are assessed in the SAR Test Report.
- 6. Input.power.limit parameter for 5G mmW NR radio was calculated in RF Exposure Part 0 test report.
- 7. This device is enabled with Qualcomm<sup>®</sup> Smart Transmit feature to control and manage transmitting power in real time and to ensure that the time-averaged RF exposure from WWAN is in compliance with FCC requirements. Per FCC guidance for devices enabled with Qualcomm<sup>®</sup> Smart Transmit feature, 4G LTE/5G NR FR1 and 5G mmW NR FR2 simultaneous transmission scenario does not need to be evaluated under Total Exposure Ratio (TER). The validation of the time-averaging algorithm and compliance under the Tx varying transmission scenario for WWAN technologies are reported in Part 2 report.
- Per FCC guidance for devices enabled with Qualcomm<sup>®</sup> Smart Transmit feature, simultaneous transmission analysis is evaluated by combining the exposure from each WWAN and WLAN antenna. 5G mmW NR and WLAN simultaneous transmission scenario is evaluated under the Total Exposure Ratio (TER) Appendix.
- 9. The Beam IDs with one of the highest initial simulated power density for that surface and distance was selected for Part 1 Power Density measurements.
- 10. The device was configured to transmit CW wave signal for testing. Per FCC guidance for devices enabled with Qualcomm<sup>®</sup> Smart Transmit feature, additional testing was not required for different modulations (CP-OFDM: QPSK, 16QAM, 64QAM, 256QAM, DFT-s-OFDM: PI/2 BPSK, QPSK, 16QAM, 64QAM, 256QAM), RB configurations, component carriers, channel configurations (low channel, mid channel, high channel) since the smart transmit algorithm monitors powers on a per symbol basis, which is independent of these signal characteristics.
- 11. The device was configured to MIMO configuration with H and V polarization beams transmitting together.
- 12. Additional power density measurements for front side of antenna N at band n260 were evaluated to confirm meausred psPD was not higher than the adjusted reported psPD for those specific beams (Appendix C contains more information).
- 13. When additional sides are tested at a distance further than 2mm, the beam ID with the highest ratio of simulated power density of the tested distance to worst case 2mm was selected for power density measurements for that specific side and distance.

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# 6 COMBINED PD VERIFICATIONS

This device supports GEN2 Smart Transmit. The following verifications were performed per 80-w2112-4.

Measured psPD results in the below verifications were measured at a reduced power level as per the manufacturer. All psPD values were scaled to reflect the original input.power.limit (before permanent back-off applied) corresponding to the PD\_design\_target. The permanent back-off values are included in the Part 0 test report.

### 6.1 Verification Criteria 1 (Power Density per beam):

The measured psPD results from the previous section are confirmed to meet:

Measured  $psPD \leq (b_i * PD\_design\_target + total uncertainty) < FCC psPD limit$ 

r													
	PD_design_	_target (mW	//cm²)	0.631									
	Total ur	certainty (	1B)	2.0									
Band	Antenna	Antenna Type	Printed backoff value b <sub>j</sub>	Beam ID 1	Beam ID 2	Measured psPD (mW/cm <sup>2</sup> )	psPD scaled to input.power.limit without permanent backoff (mW/cm <sup>2</sup> )	b <sub>j</sub> * PD_design_target + total uncertainty (mW/cm <sup>2</sup> )	FCC psPD Limit (mW/cm <sup>2</sup> )				
n258	М	Patch	0.955	-	156	0.453	0.508	0.955	1				
n258	N	Patch	0.9333	31	-	0.399	0.448	0.933	1				
n261	М	Patch	0.955	-	162	0.504	0.565	0.955	1				
n261	N	Patch	0.9333	-	160	0.519	0.582	0.933	1				
n260	М	Patch	0.955	-	152	0.348	0.390	0.955	1				
n260	N	Patch	0.9333	40	-	0.212	0.267	0.933	1				

Table 6-1 5G mmWave NR mmWave Power Density Per Beam

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## 6.2 Verification Criteria 2 (combined Power Density):

Combined Power Density results in the below tables are confirmed to meet:

combined  $psPD = (c(p, j) * measured. psPD. beam_p + c(q, j) * measured. psPD. beam_q)$  $\leq PD_design_target + total uncertainty$ 

where,

*meas.* psPD.  $beam_i = measured 4cm^2 PD$  for beam i, i = p, q $c(i, j) = contribution factor from <math>beam_i$  to  $antenna_j, i = p, q$  and j = 0, 1

Beam<sub>p</sub> = beam having the highest measured psPD among all beams tested for first antenna Beam<sub>q</sub> = beam having the highest measured psPD among all beams tested for second antenna

	5G mmwave NR mmwave Highest Measured psPD							
Band	Antenna	Antenna Type	Beam ID 1	Beam ID 2	Surface	Measured psPD (mW/cm <sup>2</sup> )	psPD scaled to input.power.limit without permanent backoff (mW/cm <sup>2</sup> )	
n258	М	Patch	-	156	Back	0.453	0.508	
n258	N	Patch	38	-	Back	0.223	0.250	
n258	N	Patch	31	-	Right	0.399	0.448	
n261	М	Patch	-	162	Back	0.504	0.565	
n261	N	Patch	-	160	Right	0.519	0.582	
n260	М	Patch	-	152	Back	0.348	0.390	
n260	N	Patch	30	-	Back	0.188	0.237	
n260	N	Patch	21	-	Front	0.191	0.240	
n260	N	Patch	40	-	Right	0.212	0.267	

Table 6-25G mmWave NR mmWave Highest Measured psPD

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	<b>Contribution Factors per module location</b>						
Beam ID	М	Ν					
	Back	Back					
156	1	0.0689					
38	0.019	0.1746					
ied psPD /cm <sup>2</sup> )	0.513	0.079					
n_target + certainty] (cm <sup>2</sup> )	1	1					
	Beam ID 156 38 ed psPD /cm <sup>2</sup> ) n_target + certainty] /cm <sup>2</sup> )	Beam IDContribution FactorsBeam IDMBack1561380.019ed psPD0.513/cm²)0.513n_target +1:ertainty]1					

Table 6-3 **Combined Power Density Band n258** 

		Contribution Factors per module location			
Band	Beam ID	М	Ν		
		Back	Right		
n7E0	156	1	0.0261		
11258	31	0.006	1		
Combined psPD (mW/cm <sup>2</sup> )		0.511	0.461		
[PD_design_target + total uncertainty] (mW/cm <sup>2</sup> )		1	1		

Table 6-4 **Combined Power Density Band n261** 

		<b>Contribution Factors per module location</b>			
Band	Beam ID	М	Ν		
		Back	Right		
n761	162	1	0.0013		
11201	160	0.0033	1		
Combined psPD (mW/cm <sup>2</sup> )		0.567	0.583		
[PD_design_target + total uncertainty] (mW/cm <sup>2</sup> )		1	1		

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		<b>Contribution Factors</b>	per module location		
Band	Beam ID	М	Ν		
		Back	Front		
n260	152	1	0.0041		
n260	21	0.001	0.5905		
Combir (mW	ned psPD //cm <sup>2</sup> )	0.391	0.144		
[PD_design_target + total uncertainty] (mW/cm <sup>2</sup> )		1	1		

Table 6-5 **Combined Power Density Band n260** 

		Contribution Factors per module location			
Band	Beam ID	М	Ν		
		Back	Back		
n260	152	1	0.0018		
11260	30	0.0021	0.4616		
Combined psPD (mW/cm <sup>2</sup> )		0.391	0.110		
[PD_design_target + total uncertainty] (mW/cm <sup>2</sup> )		1	1		

		<b>Contribution Factors per module location</b>			
Band	Beam ID	М	N		
		Back	Right		
250	152	1	0.0037		
11260	40	0.0033	1		
Combined psPD (mW/cm <sup>2</sup> )		0.391	0.268		
[PD_design_target + total uncertainty] (mW/cm <sup>2</sup> )		1	1		

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#### 7 **EQUIPMENT LIST**

Manufacturer	Model	Description	Cal Date	Cal Interval	Cal Due	Serial Number
-	WL25-1	Conducted Cable Set (25GHz)	N/A	N/A	N/A	WL25-1
-	WL40-1	Conducted Cable Set (40GHz)	N/A	N/A	N/A	WL40-1
Agilent	N9038A	MXE EMI Receiver	N/A	N/A	N/A	MY51210133
Agilent	N9030A	PXA Signal Analyzer (44GHz)	N/A	N/A	N/A	MY52350166
EMCO	3160-09	Small Horn (18 - 26.5GHz)	N/A	N/A	N/A	00135427
Emco	3116	Horn Antenna (18 - 40GHz)	N/A	N/A	N/A	9203-2178
Rohde & Schwarz	SFUNIT-Rx	Shielded Filter Unit	N/A	N/A	N/A	102133
Rohde & Schwarz	FSW67	Signal / Spectrum Analyzer	N/A	N/A	N/A	103200
SPEAG	EUmmWV4	EUmmWV4 Probe	01/11/2021	Annual	01/11/2022	9523
SPEAG	SM 003 100 AA	30 GHz System Verification Ka- Band Source Antenna	12/10/2020	Annual	12/10/2021	1045
SPEAG	DAE4ip	Dasy Data Acquisition Electronics	11/17/2020	Annual	11/17/2021	1639
SPEAG	EUmmWV4	EUmmWV4 Probe	05/20/2021	Annual	05/20/2022	9541
SPEAG	DAE4	Dasy Data Acquisition Electronics	02/12/2021	Annual	02/12/2022	665
SPEAG	EUmmWV3	EUmmWV3 Probe	11/16/2020	Annual	11/16/2021	9389
SPEAG	SM 003 100 AA	30 GHz System Verification Ka- Band Source Antenna	02/10/2021	Annual	02/10/2022	1035
SPEAG	DAE4ip	Dasy Data Acquisition Electronics	11/17/2020	Annual	11/17/2021	1638
Emco	3115	Horn Antenna (1-18GHz)	N/A	N/A	N/A	9704-5182
Keysight Technologies	N9030A	3Hz-44GHz PXA Signal Analyzer	N/A	N/A	N/A	MY49430494
Keysight Technologies	N9030A	3Hz-44GHz PXA Signal Analyzer	N/A	N/A	N/A	MY49430244
Rohde & Schwarz	180-442-KF	Horn (Small)	N/A	N/A	N/A	U157403-01
Rohde & Schwarz	ESU26	EMI Test Receiver (26.5GHz)	N/A	N/A	N/A	100342
Rohde & Schwarz	SFUNIT-Rx	Shielded Filter Unit	N/A	N/A	N/A	102134
Sunol	JB5	Bi-Log Antenna (30M - 5GHz)	N/A	N/A	N/A	A051107
Virginia Diodes Inc	SAX252	Spectrum Analyzer Extension Module	N/A	N/A	N/A	SAX252
Virginia Diodes Inc	SAX253	Spectrum Analyzer Extension Module	N/A	N/A	N/A	SAX253
Virginia Diodes Inc	SAX254	Spectrum Analyzer Extension Module	N/A	N/A	N/A	SAX254

### Table 7-1 5G mmWave NR Equipment List

Note:

1. Each equipment item was used solely within its respective calibration period.

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#### 8 **MEASUREMENT UNCERTAINTIES**

a	b	с	d	е	f =	g	
					c x f/e	0	
	Unc.	Prob.			u:		
Uncertainty Component	(± dB)	Dist.	Div.	Ci	(± dB)	v <sub>i</sub>	
Calibration	0.49	N	1	1	0.49	∞	
Probe Correction	0.00	R	1 73	1	0.00	∞	
Frequency Response	0.00	R	1.73	1	0.00	∞	
Sensor Cross Counting	0.00	R	1.73	1	0.00	∞	
Isotropy	0.50	R	1.73	1	0.29	∞	
Linearity	0.20	R	1.73	1	0.12	∞	
Probe Scattering	0.00	R	1.73	1	0.00	∞	
Probe Positioning offset	0.30	R	1.73	1	0.17	∞	
Probe Positioning Repeatability	0.04	R	1.73	1	0.02	∞	
Sensor MechanicalOffset	0.00	R	1.73	1	0.00	∞	
Probe Spatial Resolution	0.00	R	1.73	1	0.00	∞	
Field Impedence Dependance	0.00	R	1.73	1	0.00	∞	
Amplitude and Phase Drift	0.00	R	1.73	1	0.00	∞	
Amplitude and Phase Noise	0.04	R	1.73	1	0.02	∞	
Measurement Area Truncation	0.00	R	1.73	1	0.00	∞	
Data Acquisition	0.03	N	1	1	0.03	∞	
Sampling	0.00	R	1.73	1	0.00	∞	
Field Reconstruction	0.60	R	1.73	1	0.35	∞	
Forward Transformation	0.00	R	1.73	1	0.00	∞	
Power Density Scaling	0.00	R	1.73	1	0.00	∞	
Spatial Averaging	0.10	R	1.73	1	0.06	∞	
System Detection Limit	0.04	R	1.73	1	0.02	∞	
Test Sample Related							
Probe Coupling with DUT	0.00	R	1.73	1	0.00	∞	
Modulation Response	0.40	R	1.73	1	0.23	∞	
Integration Time	0.00	R	1.73	1	0.00	∞	
Response Time	0.00	R	1.73	1	0.00	∞	
Device Holder Influence	0.10	R	1.73	1	0.06	∞	
DUT alignment	0.00	R	1.73	1	0.00	∞	
RF Ambient Conditions	0.04	R	1.73	1	0.02	8	
Ambient Reflections	0.04	R	1.73	1	0.02	∞	
Immunity/Secondary Reception	0.00	R	1.73	1	0.00	∞	
Drift of DUT	0.21	R	1.73	1	0.12	∞	
Combined Standard Uncertainty (k=1) RSS						~	
Expanded Uncertainty k=2					1.52		
(95% CONFIDENCE LEVEL)							

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# 9 CONCLUSION

### 9.1 Measurement Conclusion

The power density measurements and total exposure ratio analysis indicate that the DUT complies with the RF radiation exposure limits of the FCC, with respect to all parameters subject to this test. These measurements were taken to simulate the RF effects of RF exposure under worst-case conditions. Precise laboratory measures were taken to assure repeatability of the tests. The results and statements relate only to the item(s) tested.

Please note that the RF Exposure and distribution of electromagnetic energy in the body are very complex phenomena that depend on the mass, shape, and size of the body, the orientation of the body with respect to the field vectors, and the electrical properties of both the body and the environment. Other variables that may play a substantial role in possible biological effects are those that characterize the environment (e.g. ambient temperature, air velocity, relative humidity, and body insulation) and those that characterize the individual (e.g. age, gender, activity level, debilitation, or disease). Because various factors may interact with one another to vary the specific biological outcome of an exposure to electromagnetic fields, any protection guide should consider maximal amplification of biological effects as a result of field-body interactions, environmental conditions, and physiological variables.

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